

AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in this application:

LISTING OF CLAIMS:

Claims 1 to 14. (Canceled).

15. (Previously Presented) A method for testing a measuring system for correct functioning, comprising:

in a normal operation of the measuring system, transmitting, by a measurement device to a second device via a data-transmission device, a bit having a constant level to signal a fault-free operation of the measuring device;

in a test operation of the measuring system:

electrically contacting a signal-monitoring circuit of the measuring device with a test-potential source; and

in the second device, checking whether the test operation effects a change in a level of the bit in relation to the level of the bit in the normal operation; and

outputting test data conditional upon a determination that the change has not been effected.

16. (Previously Presented) The method according to claim 15, wherein in the normal operation of the measuring system a change in the level of the bit triggers a reaction in the second device, in the test operation, the change in the level of the bit does not trigger any reaction in the second device.

17. (Previously Presented) The method according to claim 15, further comprising electrically contacting the test-potential source and the signal-monitoring circuit in response to a signal from the second device.

18. (Previously Presented) The method according to claim 15, further comprising automatically triggering the test operation in defined time intervals to test the measuring device for correct functioning.

19. (Previously Presented) The method according to claim 15, further comprising manually triggering the test operation to test the measuring device for correct functioning.

20. (Previously Presented) The method according to claim 15, further comprising automatically triggering the test operation to test the measuring device for correct functioning in response to specific machine states being reached.

21. (Previously Presented) The method according to claim 20, wherein the specific machine states includes at least one of (a) a tool change and (b) a workpiece change.

Claims 22 and 23. (Canceled).

24. (Previously Presented) The method according to claim 15, wherein the test data is generated in the test operation of the measuring system, in the second device, and is indicative of a result of the checking.